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Inventor            Louis G. Carreiro

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AN IMPROVED SYSTEM AND APPARATUS FOR MEASURING  
DISPLACEMENTS IN ELECTRO-ACTIVE MATERIALS

TO ALL WHOM IT MAY CONCERN

BE IT KNOWN THAT LOUIS G. CARREIRO employee of the United States Government, AND LAWRENCE J. REINHART, citizens of the United States of America, and residents respectively of Westport, County of Bristol, Commonwealth of Massachusetts and Wilmington, County of Middlesex, Commonwealth of Massachusetts, have invented certain new and useful improvements entitled as set forth above of which the following is a specification:

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AN IMPROVED SYSTEM AND APPARATUS FOR MEASURING

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DISPLACEMENTS IN ELECTRO-ACTIVE MATERIALS

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STATEMENT OF GOVERNMENT INTEREST

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The invention described herein may be manufactured and used

8

by or for the Government of the United States of America for

9

governmental purposes without the payment of any royalties

10

thereon or therefore.

11

12

CROSS REFERENCE TO OTHER RELATED APPLICATIONS

13

This patent application is co-pending with a related patent

14

application entitled A SYSTEM AND APPARATUS FOR MEASURING

15

DISPLACEMENTS IN ELECTRO-ACTIVE MATERIALS (Navy Case No. 84273),

16

by Louis G. Carreiro and Lawrence J. Reinhart both of whom are

17

inventors as to this application.

18

19

BACKGROUND OF THE INVENTION

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(1) Field of the Invention

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The present invention relates to a device for measuring

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displacements in a solid material, and more specifically to a device

23

for applying uniaxial hydraulic pressure to the surfaces of an

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electro-active material while at the same time permitting a light

1 source to be focused on the same surfaces in order to perform non-  
2 contact displacement measurements of the material under controlled  
3 conditions of pressure, temperature and applied voltage.

#### 4 (2) Description of the Prior Art

5 The active elements of most sonar transducers consist of  
6 rings, disks or plates fabricated with electro-active (piezo-  
7 electric and electrostrictive) ceramics such as lead zirconium  
8 titanate (PZT) and with emerging materials such as the solid  
9 solution of lead magnesium niobate and lead titanate (PMN-PT).  
10 In a common configuration, these elements are bonded together  
11 with epoxy to form a stack that is then placed under a  
12 compressive load. When the stack is electrically driven, the  
13 applied compressive force opposes the tensile stress (internal  
14 strain) generated in the ceramic. This arrangement prevents the  
15 ceramic from going into tension and thus reduces the chance of  
16 failure due to fracturing.

17 Attempts to measure the electromechanical properties of  
18 stack elements often result in data that is difficult to  
19 interpret since the epoxy adhesive, metal electrodes and  
20 compression fixture tend to mask the properties of the ceramic.  
21 Therefore, a device for the direct characterization of the pre-  
22 stressed ceramic that eliminates the unwanted contributions from  
23 the stack assembly components is needed.

1       Currently, there exists a quasi-static apparatus used to  
2 determine the 33-mode properties of electro-active ceramics  
3 under simultaneous conditions of high electrical drive,  
4 electrical bias, compressive load and temperature.

5       With the quasi-static apparatus, a sample with dimensions  
6 of 2 mm x 2 mm x 10 mm (an aspect ratio of 5:1 ensures 33-mode  
7 operation) is placed under a unidirectional compressive load  
8 along its length. The pre-stress is applied over a range of 0  
9 to 10 ksi with a pneumatic piston designed to have low  
10 mechanical loss and low ac stiffness so that a "constant stress"  
11 boundary condition is met. The entire apparatus is placed in an  
12 environmental chamber in order to obtain data versus  
13 temperature. The sample is then electrically driven with a 10  
14 Hz sine wave of the order of 2.0 Mv/m. The charge versus  
15 applied field is measured using an integrating capacitor, and  
16 the longitudinal strain versus field is measured with strain  
17 gauges attached to the sides of the sample. From these  
18 measurements, the large signal dielectric constant,  $\epsilon_{33}^T$ , the  
19 piezoelectric constant  $d_{33}$ , and the coupling factor,  $k_{33}$ , can be  
20 calculated as a function of drive signal, bias field, pre-stress  
21 and temperature. Young's modulus is obtained from the  
22 measurement of strain versus applied stress.

23       The device described above has several limitations. The  
24 required geometry and small sample size often cause problems with

1 mechanical alignment, and under compressive load, samples are prone  
2 to mechanical cracking and electrical breakdown. Precise attachment  
3 of the strain gauges to the samples is difficult, affecting the  
4 reproducibility of the measurements from sample to sample.  
5 Furthermore, the gauges introduce stray capacitance, and due to their  
6 close proximity, exhibit electrical cross talk and promote electrical  
7 discharge arcing. Since temperature is controlled via an  
8 environmental chamber, long equilibration times are required before  
9 data can be acquired. In addition, temperature gradients within the  
10 chamber also affect the ability to repeat the measurements. For the  
11 most part, this apparatus lacks the reliability and precision that is  
12 necessary to characterize electro-active ceramics in a reproducible  
13 and efficient manner. What is needed is a device for applying  
14 uniaxial hydraulic pressure to the surface of an electro-active  
15 material while at the same time performing non-contact displacement  
16 measurements of the material under controlled conditions of pressure,  
17 temperature and applied voltage.

#### 18 19 SUMMARY OF THE INVENTION

20 It is a general purpose and object of the present invention to  
21 provide a means of measuring displacement in electro-active material  
22 under applied voltage through the application of a uniaxial constant  
23 force without the use of strain gauges.

1        It is a further object to provide a means of measuring  
2 ~~displacement in electro-active material through a non-contact means~~  
3        such as laser interferometry.

4 Another object is to provide a means for measuring displacement  
5 in electro-active material that will not subject samples of the  
6 material to mechanical fracturing and electrical breakdown.

7 Another object is to provide a means for measuring displacement  
8 in electro-active material without the use of an environmental  
9 chamber.

10 Another object is to provide a means for measuring displacement  
11 in electro-active material on more than one side of the material.

12        Still another object is to provide a means for measuring  
13        displacement in electro-active material that will ensure  
14        reproducibility of the measurements from sample to sample.

15           These objects are accomplished with the present invention  
16 through a high pressure optical cell, in conjunction with a laser  
17 interferometer system. The cell provides a means for non-contact  
18 displacement measurements of electro-active (piezoelectric and  
19 electrostrictive) materials to be performed under controlled  
20 conditions of pressure, temperature and applied voltage.

21

22 BRIEF DESCRIPTION OF THE DRAWINGS

23           A more complete understanding of the invention and many of  
24   the attendant advantages thereto will be readily appreciated as

1 the same becomes better understood by reference to the following  
2 detailed description when considered in conjunction with the  
3 accompanying drawings wherein:

4 FIG. 1 shows a schematic drawing of the high pressure  
5 optical cell in use with the cell halves closed;

6 FIG. 2 shows a schematic drawing of the high pressure  
7 optical cell in use with the cell halves opened;

8 FIG. 3 shows a cross section of the high pressure optical  
9 cell containing the sample and dielectric oil;

10 FIG. 4 shows a cross section close-up of the chamber of the  
11 high pressure optical cell;

12 FIG. 5 shows a block diagram of the connections between the  
13 various components in the system controlled by a central  
14 processing unit.

15

#### 16 DESCRIPTION OF THE PREFERRED EMBODIMENT

17 Referring now to FIG. 1 there is shown a high pressure  
18 optical cell 10. In the preferred embodiment, the cell 10  
19 consists of two symmetrical cell halves, 10a and 10b. The cell  
20 10 is fabricated from stainless steel, however, it is to be  
21 understood that the present device is not limited to that  
22 particular metal alloy and could be made of titanium or other  
23 materials capable of containing fluid at high pressures.  
24 Referring now to FIG. 2, there is shown the constituent



1 components of the cell 10 designed to contain a sample 20 of  
2 electro-active material for displacement measurement in  
3 conjunction with laser interferometer 12. In the preferred  
4 embodiment, the cell 10 accommodates a sample 20 with cross-  
5 sectional areas of 0.25 to 1.0 in<sup>2</sup> and thickness of 0.1 to 0.25  
6 inches. The two halves of the cell 10a and 10b are kept closed  
7 by bolts 48 that are tightened at a specified torque. The cell  
8 10 is mounted onto a three-way high precision optical stage (not  
9 shown), with tilt and yaw capability, which is positioned in the  
10 beam path of the laser interferometer 12. This embodiment is  
11 based on an interferometer 12 configured for two beams 14a, 14b.  
12 Dual-beam interferometric measurements in which a first beam 14a  
13 reflects off one surface of sample 20 and a second beam 14b  
14 reflects off the opposite surface of sample 20 at the same  
15 position and axial point spatially as the first beam 14a  
16 provides a method for probing the symmetry of the displacement  
17 of sample 20.

18 Referring now to FIG. 3 and FIG. 4, it is shown that when  
19 the symmetrical cell halves 10a and 10b are closed and bolted,  
20 the cell 10 forms an interior cavity 22. Two quartz glass  
21 windows 18a and 18b are contained at opposite sides of the  
22 cavity 22, one in each of the respective cell halves 10a and  
23 10b. The windows 18a and 18b are designed to be transparent to  
24 laser radiation of a particular wavelength. In the preferred

1 embodiment, the wavelength is  $\lambda = 632$  nm, but is not limited as  
2 such. It should be understood that the present device is not  
3 limited to the use of quartz glass for the windows 18a, 18b and  
4 could be made of other optically transparent materials,  
5 providing said materials are transparent to the laser radiation  
6 in use. The windows 18a, 18b have an anti-reflective coating  
7 24a and 24b on each of their respective surfaces transparent to  
8 light of the same wavelength as the laser beams 14a, 14b to  
9 prevent multiple reflections in the cavity 22 that might give  
10 rise to false signals to the interferometer 12.

11 Shim stops 16 are positioned between the two cell halves  
12 10a and 10b that match various sample thickness in order to  
13 prevent crushing of the sample 20 when the cell halves 10a and  
14 10b are in a closed position. The sample 20 is positioned  
15 within the cavity 22 between two piston seals 42a and 42b. In  
16 the preferred embodiment, the seals 42a, 42b are made of glass-  
17 filled Teflon®. The piston seals 42a, 42b are designed to be  
18 interchangeable to match a given size and shape of sample 20,  
19 thus insuring a proper seal contact to minimize edge effects.

20 Once the sample 20 is properly placed within the cell 10 at  
21 the center of cavity 22, the cavity 22 is then filled with a  
22 high dielectric oil 26 with matching index of refraction ( $n =$   
23 1.458) to that of the quartz windows 18a and 18b. The high  
24 dielectric oil 26 is introduced into the cavity 22 through the

1 liquid pressure inlet/outlet ports 28 on each half of the cell  
2 10 from a pressure pump control system 30 that generates and  
3 controls the hydraulic pressure. In the preferred embodiment,  
4 the pressure pump control system 30 is capable of generating up  
5 to 60 ksi of pressure. Once the cavity 22 is filled with oil 26  
6 at a specified pressure, both surfaces of the sample 20 are  
7 subjected to a uniform uniaxial pressure leaving the outer  
8 perimeter surfaces of the sample 20 at room pressure.

9 Referring now to FIG. 3, FIG. 4 and FIG. 5, it is shown  
10 that thermoelectric coolers/heaters 32 are mounted onto the cell  
11 housing surrounding the cavity 22 to provide precise control of  
12 the temperature of both the dielectric oil 26 and the sample 20.  
13 A cooling water heat sink 34 is used to remove heat generated by  
14 the thermoelectric coolers/heaters 32. A thermoelectric  
15 controller 36 is used in conjunction with thermistors 38 to  
16 achieve accurate temperature control. A surrounding layer of  
17 insulation 40 assists in maintaining constant temperature  
18 conditions. The combination of thermoelectric coolers/heaters  
19 32, cooling water heat sink 34, insulation 40, thermistors 38  
20 and thermoelectric controller 36 allow the cell 10 to function  
21 as a miniature self-contained thermal control system.

22 Tension-spring wires 44a and 44b located in either side of  
23 cavity 22 make electrical contact with the sample 20,  
24 eliminating the need for solder connections to the test sample.

1 The ends of the wire 44a and 44b that make electrical contact  
2 with the sample 20 are gold-plated and interchangeable. The  
3 contact heads can be pointed, flat, rounded or whatever geometry  
4 is required to insure a positive, continuous electrical contact  
5 to the sample. The other end of the wires 44a and 44b are  
6 electrically connected to a blocking circuit 50 and a high  
7 voltage power supply 52.

8 Referring now to FIG. 5, the cell 10, interferometer 12,  
9 thermoelectric controller 36, blocking circuit 50, voltage power  
10 supply 52 and pressure pump control system 30 are interfaced to  
11 a central processing unit 46 such as a computer that controls  
12 and monitors system components and experimental parameters.

13 In operation, the entire system functions as follows: The  
14 sample 20 is placed between piston seals 42a and 42b and  
15 positioned between the two cell halves 10a and 10b. The cell  
16 halves 10a and 10b are aligned and bolted. The electrical  
17 connections are made from the cell 10 to the blocking circuit 50  
18 and high voltage power supply 52 via the tension spring wires  
19 44a and 44b. Thermoelectric heaters/coolers 32 along with  
20 thermistors 38 are connected to the thermoelectric controller  
21 39. Cooling water is connected to the cooling water heat sink  
22 34. Pressure lines 29 are attached from the pressure pump  
23 control system 30 to the liquid pressure inlet/outlet ports 28,  
24 and the cavity 22 is flooded with the high-dielectric oil 26

1 while allowing air to bleed from the cavity 22. The cavity 22  
2 is pressurized to the desired level and the cell 10 is optically  
3 aligned to the interferometer 12. Finally, the cell 10 is  
4 heated to the proper temperature and a voltage is applied to the  
5 sample 20 as the interferometer 12 measures the displacement of  
6 the sample 20.

7 This invention has several distinct advantages over the  
8 prior art. The present invention utilizes a non-contact method  
9 that measures strain via a laser interferometer, unlike the  
10 prior art methods that employs strain gauges physically attached  
11 to the sample. Use of a laser interferometer allows  
12 measurements to be performed with nanometer resolution.

13 Unidirectional pre-stresses of up to 20 ksi are applied  
14 using hydraulic fluid rather than mechanical compression. Since  
15 the ends of the sample are not clamped (between the platens of a  
16 press) they are free to move, eliminating the need for  
17 geometries with fixed aspect ratios. The present invention  
18 offers a variable frequency range of 1.0 Hz to 20 kHz and is not  
19 limited to a single operating frequency.

20 Temperature of the sample is precisely controlled with  
21 thermoelectric heaters and coolers, and is accurately monitored  
22 by thermistors placed in close proximity to the sample. The  
23 precision afforded by the thermal control elements built  
24 directly into the cell 10 provides an accuracy in temperature

1 and speed of use that would otherwise be impossible to attain  
2 through the use of an environmental chamber.

3 Measurement of 31-mode properties (in addition to 33-mode)  
4 is possible. Double-sided measurements can be carried out to  
5 determine displacement symmetries on both faces of the sample  
6 simultaneously. Since the laser beam can be positioned anywhere  
7 on the surface of the sample, homogeneity of the surface can be  
8 evaluated.

9 What has thus been described is a device for applying  
10 uniaxial hydraulic pressure to the surfaces of an electro-active  
11 material while at the same time permitting a light source to be  
12 focused on the same surfaces in order to perform non-contact  
13 displacement measurements of the material under controlled  
14 conditions of pressure, temperature and applied voltage.

15 Obviously many modifications and variations of the present  
16 invention may become apparent in light of the above teachings.  
17 For example the cell may be made of various materials capable of  
18 withstanding high pressures. The dielectric fluid can be chosen  
19 from any of a number of fluids. The optical aperture may be  
20 made of any suitable optically transparent material. The laser  
21 frequency of the interferometer can vary according to the type  
22 of measurements taken.

1        In light of the above, it is therefore understood that  
2        within the scope of the appended claims, the invention may be  
3        practiced otherwise than as specifically described.

2

3 AN IMPROVED SYSTEM AND APPARATUS FOR MEASURING  
4 DISPLACEMENTS IN ELECTRO-ACTIVE MATERIALS

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6 ABSTRACT OF THE DISCLOSURE

7 A specialized containment cell with optically transparent  
8 apertures, in conjunction with a laser interferometer system provides  
9 the means for non-contact displacement measurements of electro-active  
10 (piezoelectric and electrostrictive) materials to be performed under  
11 controlled conditions of pressure, temperature and applied voltage.

12 A sample of electro-active material is placed inside the cell.

13 Electrical connections are made from a high voltage power source to  
14 the sample through the cell. Thermoelectric heaters/coolers and a  
15 cooling water heat sink built into the cell control the temperature  
16 of the sample. The cell is flooded with a dielectric oil  
17 pressurizing the interior of the cell to a desired pressure. The  
18 cell is optically aligned to the interferometer, and with the cell  
19 heated to the proper temperature, a voltage is applied to the sample  
20 as the interferometer measures the displacement of the sample.



Declaration and Power of Attorney For Utility or Design Patent Application

As a below named inventor, I hereby declare that:

My residence, post office address and citizenship are as stated below next to my name. I believe I am original, first and joint inventor with Lawrence J. Reinhart of the subject matter which is claimed and for which a patent is sought on the invention entitled: **AN IMPROVED SYSTEM AND APPARATUS FOR MEASURING DISPLACEMENTS IN ELECTRO-ACTIVE MATERIALS**, the specification of which:

(check one) [X] is attached hereto.

[ ] was filed on \_\_\_\_\_ as  
Application Serial No. \_\_\_\_\_  
and was amended on \_\_\_\_\_

I hereby state that I have reviewed and understand the contents of the above identified specification, including the claims, as amended by any amendment referred to above.

I acknowledge the duty to disclose information which is material to patentability as defined in 37 CFR 1.56, including for continuation-in-part applications, material information which became available between the filing date of the prior application and the national or PCT international filing date of the continuation-in-part application:

I hereby claim foreign priority benefits under 35 U.S.C. 119(a)-(d) or (f) of any foreign application(s) for patent, inventor's or plant breeder's rights certificate(s), or 365(a) of any PCT international application which designated at least one country other than the United States of America, listed below and have also identified below, by checking the box, any foreign application for patent, inventor's or plant breeder's right certificate(s), or any PCT international application having a filing date before that of the application on which priority is claimed:

Prior Foreign Applications			Priority Claimed		Certified Copy Attached	
(Number)	(Country)	(Day/Month/Year Filed)	Yes	No	Yes	No

**POWER OF ATTORNEY:** As a named inventor, I hereby appoint the following attorneys to prosecute this application and transact all business in the Patent and Trademark Office connected therewith, and hereby certify that the Government of the United States has the irrevocable right to prosecute this application:

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I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

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Inventor's signature *Louis G. Carreiro*

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Declaration and Power of Attorney For Utility or Design Patent Application

As a below named inventor, I hereby declare that:

My residence, post office address and citizenship are as stated below next to my name. I believe I am original, second and joint inventor with LOUIS G. CARREIRO of the subject matter which is claimed and for which a patent is sought on the invention entitled: **AN IMPROVED SYSTEM AND APPARATUS FOR MEASURING DISPLACEMENTS IN ELECTRO-ACTIVE MATERIALS**, the specification of which:

(check one) ☒ is attached hereto.

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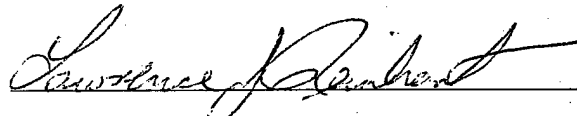
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I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code, and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

Full name of second inventor: LAWRENCE J. REINHART

Inventor's signature



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